

IRFP460C

500V N-Channel MOSFET

General Description

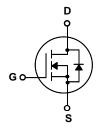
These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switch mode power supplies and power factor corrections.

Features

- 20A, 500V, $R_{DS(on)}$ = 0.24 Ω @V_{GS} = 10 V Low gate charge (typical 130nC)
- Low Crss (typical 60 pF)
- Fast switching
- 100% avalanche tested
- · Improved dv/dt capability





Absolute Maximum Ratings T_C = 25°C unless otherwise noted

	<u> </u>	500 20	V A
,	<u> </u>	20	А
- Continuous (T _C = 100°C	٠)		
	')	12.5	Α
Drain Current - Pulsed	(Note 1)	80	Α
Gate-Source Voltage		± 30	V
Single Pulsed Avalanche Energy	(Note 2)	1050	mJ
Avalanche Current	(Note 1)	20	Α
Repetitive Avalanche Energy	(Note 1)	23.5	mJ
Peak Diode Recovery dv/dt	(Note 3)	4.5	V/ns
Power Dissipation (T _C = 25°C) - Derate above 25°C		235	W
		1.88	W/°C
Operating and Storage Temperature Range		-55 to +150	°C
T _{STG} Operating and Storage Temperature Range Maximum lead temperature for soldering purposes,		300	°C
	Gate-Source Voltage Single Pulsed Avalanche Energy Avalanche Current Repetitive Avalanche Energy Peak Diode Recovery dv/dt Power Dissipation (T _C = 25°C) - Derate above 25°C Operating and Storage Temperature Range	Gate-Source Voltage Single Pulsed Avalanche Energy (Note 2) Avalanche Current (Note 1) Repetitive Avalanche Energy (Note 1) Peak Diode Recovery dv/dt (Note 3) Power Dissipation (T _C = 25°C) - Derate above 25°C Operating and Storage Temperature Range Maximum lead temperature for soldering purposes,	Gate-Source Voltage ± 30 Single Pulsed Avalanche Energy (Note 2) 1050 Avalanche Current (Note 1) 20 Repetitive Avalanche Energy (Note 1) 23.5 Peak Diode Recovery dv/dt (Note 3) 4.5 Power Dissipation ($T_C = 25^{\circ}C$) 235 - Derate above 25°C 1.88 Operating and Storage Temperature Range -55 to +150 Maximum lead temperature for soldering purposes,

Thermal Characteristics

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		0.53	°C/W
R _{0CS} Thermal Resistance, Case-to-Sink		0.24		°C/W
R _{θJA} Thermal Resistance, Junction-to-Ambient			40	°C/W

	Parameter	Test Conditions	3	Min	Тур	Max	Units
Off Ck	naracteristics						
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		500			V
ΔBV _{DSS}	0	V _{GS} = 0 V, I _D = 250 μA		300			V
ΔBV _{DSS} / ΔT _J	Breakdown Voltage Temperature Coefficient	$I_D = 250 \mu A$, Referenced to 25°C			0.55		V/°C
I _{DSS}	Zoro Coto Voltago Proin Current	$V_{DS} = 500 \text{ V}, V_{GS} = 0 \text{ V}$				10	μΑ
	Zero Gate Voltage Drain Current	$V_{DS} = 400 \text{ V}, T_{C} = 125^{\circ}\text{C}$;			100	μΑ
I _{GSSF}	Gate-Body Leakage Current, Forward	$V_{GS} = 30 \text{ V}, V_{DS} = 0 \text{ V}$				100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	$V_{GS} = -30 \text{ V}, V_{DS} = 0 \text{ V}$				-100	nA
On Ch	naracteristics						
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$		2.0		4.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = 10 V, I _D = 10.0 A			0.2	0.24	Ω
9 _{FS}	Forward Transconductance	$V_{DS} = 50 \text{ V}, I_{D} = 10.0 \text{ A}$	(Note 4)		18		S
		↓ f = 1.() MHz			380	460	pF
C _{rss}	Reverse Transfer Capacitance	f = 1.0 MHz			60	460 80	pF pF
	Reverse Transfer Capacitance	f = 1.0 MHz					•
Switcl	'	f = 1.0 MHz					•
Switcl	hing Characteristics	V _{DD} = 250 V, I _D = 20 A,			60	80	pF
Switcl	ning Characteristics Turn-On Delay Time				50	80	pF
Switcl t _{d(on)} t _r t _{d(off)}	hing Characteristics Turn-On Delay Time Turn-On Rise Time	V _{DD} = 250 V, I _D = 20 A,	(Note 4, 5)		50 150	80 120 310	pF ns
Switcl t _{d(on)} t _r t _{d(off)} t _{t_f}	Turn-On Rise Time Turn-Off Delay Time	$V_{DD} = 250 \text{ V}, I_{D} = 20 \text{ A},$ $R_{G} = 25 \Omega$	(Note 4, 5)	 	50 150 380	120 310 770	ns ns
Switcl t _{d(on)} t _r t _{d(off)} t _f Q _g	Turn-On Delay Time Turn-On Rise Time Turn-Off Delay Time Turn-Off Fall Time	$V_{DD} = 250 \text{ V}, I_{D} = 20 \text{ A},$ $R_{G} = 25 \Omega$ $V_{DS} = 400 \text{ V}, I_{D} = 20 \text{ A},$	(Note 4, 5)	 	50 150 380 180	120 310 770 370	ns ns ns
Switcl t _{d(on)} tr t _{d(off)} t _f Q _g Q _{gs}	Turn-On Delay Time Turn-On Rise Time Turn-Off Delay Time Turn-Off Fall Time Total Gate Charge	$V_{DD} = 250 \text{ V}, I_{D} = 20 \text{ A},$ $R_{G} = 25 \Omega$	(Note 4, 5)		50 150 380 180 130	120 310 770 370 170	ns ns ns
Switcl td(on) tr td(off) tf Qg Qgs Qgd	Turn-On Delay Time Turn-On Rise Time Turn-Off Delay Time Turn-Off Fall Time Total Gate Charge Gate-Source Charge	$V_{DD} = 250 \text{ V}, I_{D} = 20 \text{ A},$ $R_{G} = 25 \Omega$ $V_{DS} = 400 \text{ V}, I_{D} = 20 \text{ A},$ $V_{GS} = 10 \text{ V}$	(Note 4, 5)	 	50 150 380 180 130 20	120 310 770 370 170	ns ns ns ns
Switcl t _{d(on)} t _r t _{d(off)} t _f Q _g Q _{gs} Q _{gd} Drain-S	Turn-On Delay Time Turn-On Rise Time Turn-Off Delay Time Turn-Off Fall Time Total Gate Charge Gate-Source Charge Gate-Drain Charge	$V_{DD} = 250 \text{ V}, I_{D} = 20 \text{ A},$ $R_{G} = 25 \Omega$ $V_{DS} = 400 \text{ V}, I_{D} = 20 \text{ A},$ $V_{GS} = 10 \text{ V}$ and Maximum Rating	(Note 4, 5)	 	50 150 380 180 130 20	120 310 770 370 170	ns ns ns ns
Switcl td(on) tr td(off) tf Qg Qgs Qgs Qgd	Turn-On Delay Time Turn-On Rise Time Turn-Off Delay Time Turn-Off Fall Time Total Gate Charge Gate-Source Charge Gate-Drain Charge	$V_{DD} = 250 \text{ V}, I_D = 20 \text{ A},$ $R_G = 25 \Omega$ $V_{DS} = 400 \text{ V}, I_D = 20 \text{ A},$ $V_{GS} = 10 \text{ V}$ and Maximum Rating once Forward Current	(Note 4, 5)	 	50 150 380 180 130 20 45	120 310 770 370 170	ns ns ns ns nc nC
Switcl td(on) tr td(off) tf Qg Qgs Qgd Drain-S	Turn-On Delay Time Turn-On Rise Time Turn-Off Delay Time Turn-Off Fall Time Total Gate Charge Gate-Source Charge Gate-Drain Charge Source Diode Characteristics and Maximum Continuous Drain-Source Diode	$V_{DD} = 250 \text{ V}, I_D = 20 \text{ A},$ $R_G = 25 \Omega$ $V_{DS} = 400 \text{ V}, I_D = 20 \text{ A},$ $V_{GS} = 10 \text{ V}$ and Maximum Rating once Forward Current	(Note 4, 5)	 	50 150 380 180 130 20 45	120 310 770 370 170 	ns ns ns ns nC nC
t _{d(on)} t _r t _r t _{d(off)} t _f Q _g Q _{gs} Q _{gd}	Turn-On Delay Time Turn-On Rise Time Turn-Off Delay Time Turn-Off Fall Time Total Gate Charge Gate-Source Charge Gate-Drain Charge Source Diode Characteristics and Maximum Continuous Drain-Source Diode Fallows Turn-Source Diode Fallows Turn-Off Fall Time Total Gate Charge Gate-Source Charge Gate-Drain Charge	$V_{DD} = 250 \text{ V}, I_D = 20 \text{ A},$ $R_G = 25 \Omega$ $V_{DS} = 400 \text{ V}, I_D = 20 \text{ A},$ $V_{GS} = 10 \text{ V}$ and Maximum Rating ode Forward Current	(Note 4, 5)		50 150 380 180 130 20 45	120 310 770 370 170 	ns ns ns ns nC nC

- $\label{eq:Notes:1} \begin{tabular}{ll} \textbf{Notes:} \\ 1. & \textbf{Repetitive Rating: Pulse width limited by maximum junction temperature} \\ 2. & \textbf{L} = 5.1 \text{mH, } |_{AS} = 20 \text{A, } |_{DD} = 50 \text{V, } |_{RG} = 25 \ \Omega, \text{ Starting } |_{J} = 25 \ \text{°C} \\ 3. & \textbf{l}_{SD} \leq 20 \text{A, } \text{didd} \leq 200 \text{A/µs, } |_{DD} \leq \text{BV}_{DSS}, \text{ Starting } |_{J} = 25 \ \text{°C} \\ 4. & \textbf{Pulse Test: Pulse width} \leq 300 \ \mu\text{s, Duty cycle} \leq 2 \ \text{\%} \\ 5. & \textbf{Essentially independent of operating temperature} \\ \end{tabular}$

Typical Characteristics

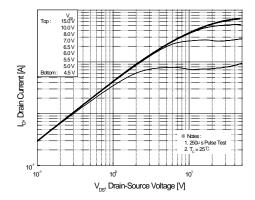


Figure 1. On-Region Characteristics

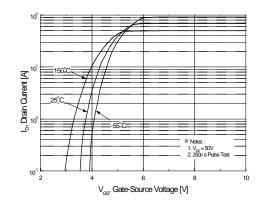


Figure 2. Transfer Characteristics

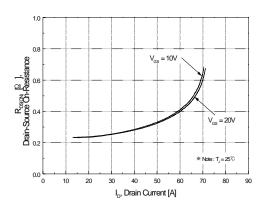


Figure 3. On-Resistance Variation vs Drain Current and Gate Voltage

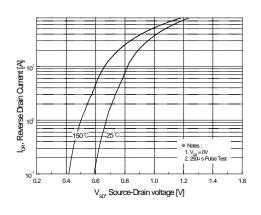


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

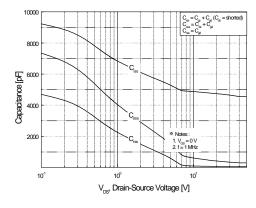


Figure 5. Capacitance Characteristics

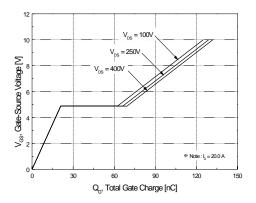
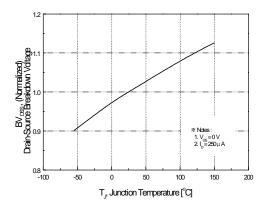


Figure 6. Gate Charge Characteristics

Dimensions in Millimeters

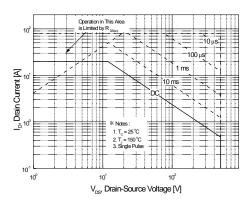
Typical Characteristics (Continued)



3.0 (OSZ) 1.0 (O

Figure 7. Breakdown Voltage Variation vs Temperature

Figure 8. On-Resistance Variation vs Temperature



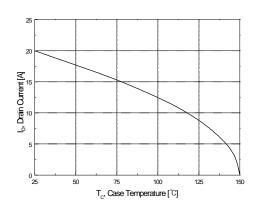


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs Case Temperature

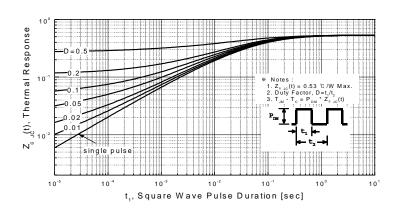
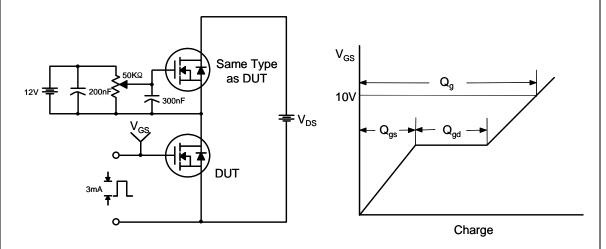


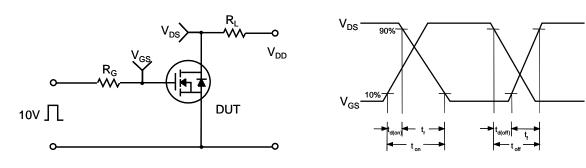
Figure 11. Transient Thermal Response Curve

Dimensions in Millimeters

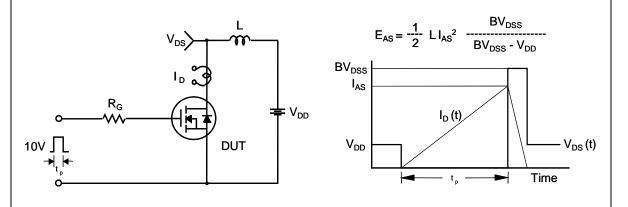
Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveforms

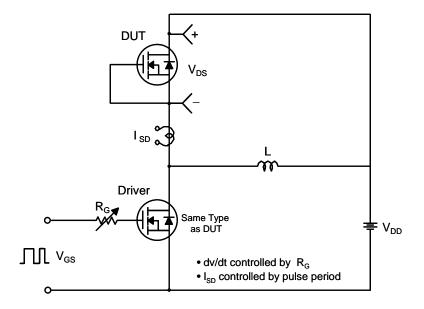


Unclamped Inductive Switching Test Circuit & Waveforms

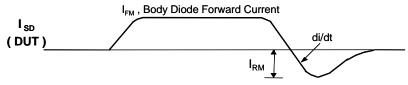


Dimensions in Millimeters

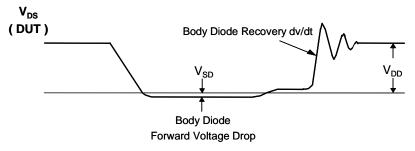
Peak Diode Recovery dv/dt Test Circuit & Waveforms





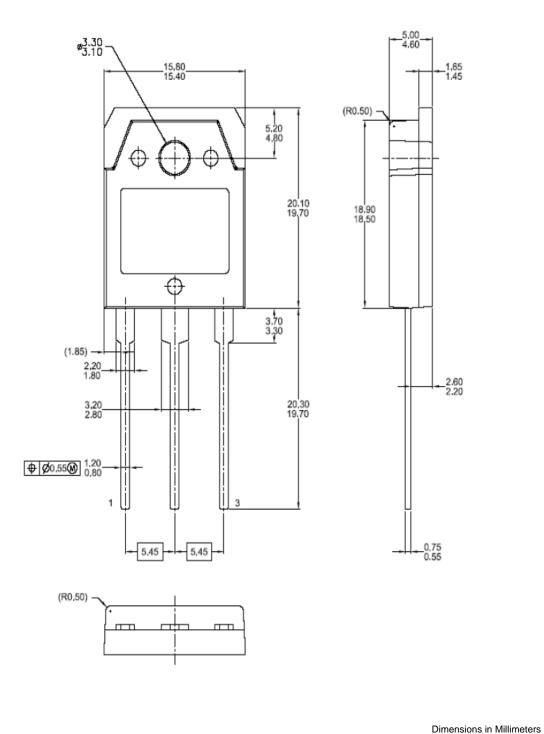


Body Diode Reverse Current



Mechanical Dimensions

TO-3PN



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